PTO/SB/08 Equivalent

INFORMATION DISCLOSURE STATEMENT BY APPLICANT		
	Application No.	10/645,331
	Filing Date	August 21, 2003
	First Named Inventor	Aydogan Ozcan
	Art Unit	2877
(Multiple sheets used when necessary)	Examiner	Sang H. Nguyen
SHEET 1 OF 2	Attorney Docket No.	STANF.131CP2

U.S. PATENT DOCUMENTS					
Examiner Initials	Cite No.	Document Number	Publication Date	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear
SN	1	3,880,630	04/29/1975	Izawa	
	2	4,985,178	01/15/1991	Tam	
	3	5,086,239	02/04/1992	Wang	
	4	5,194,918	03/16/1993	Kino et al.	
	5	5,220,451	06/15/1993	Gotoh et al.	
	6	5,239,407	08/24/1993	Brueck et al.	
	7	5,247,601	09/21/1993	Myers et al.	
	8	5,262,890	11/16/1993	Berkovic et al.	
	9	5,368,782	11/29/1994	Gotoh et al.	
	10	5,420,717	05/30/1995	Tabata	
	11	5,434,699	07/18/1995	Berkovic et al.	
	12	5,523,840	06/06/1996	Nishizawa et al.	
	13	5,615,041	03/25/1997	Field et al.	
	14	6,043,884	03/28/2000	Curbelo	
	15	6,856,393 B2	02/15/2005	Ozcan et al. (Atty. Docket No. STANF.131CP1)	
	16	2004/0036880 A1	02/26/2004	Ozcan et al. (Atty. Docket No. STANF.131A)	
SN	17	2004/0044714 A1	03/04/2004	Ozcan et al. (Atty. Docket No. STANF.131CP1)	

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials	Cite No.	Include name of the author, title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T[1]
SN	18	Fienup, J.R., "Reconstruction of an object from the modulus of its Fourier transform," Optics Letters, Vol. 3, No. 1, July 1978, pp. 27-29.	
SN	19	Ozcan, A., et al., "A simple post-processing technique to improve the retrieval accuracy of second-order nonlinearity profiles," Edward L. Ginzton Laboratory: Stanford University, Stanford, California 94305; ©2004 Optical Society of America, 2 pages.	
SN	20	Ozcan, A., et al., "Cylinder-assisted Maker-fringe Technique," Electronics Letters, Vol. 39, No. 25, 11th December 2003, 2 pages.	

Examiner Signature	Sang Nguyen	Date Considered	7/7/05

*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

T[1] - Place a check mark in this area when an English language Translation is attached.

PTO/SB/08 Equivalent

INFORMATION DISCLOSURE STATEMENT BY APPLICANT	Application No.	10/645,331
	Filing Date	August 21, 2003
	First Named Inventor	Aydogan Ozcan
	Art Unit	2877
(Multiple sheets used when necessary)	Examiner	Sang H. Nguyen
SHEET 2 OF 2	Attorney Docket No.	STANF.131CP2

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials	Cite No.	Include name of the author, title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T[1]
SN	21	Ozcan, A., et al., "Improved Fourier transform technique to determine second-order optical nonlinearity profiles," Edward L. Ginzton Laboratory: Stanford University, Stanford, California 94305; ©2003 Optical Society of America, 3 pages.	
	22	Ozcan, A., et al., "Improved technique to determine second-order optical nonlinearity profiles using two different samples," Applied Physics Letters, Vol. 84, No. 5, 2 February 2004, pp. 681-683.	
	23	Ozcan, A., et al., Erratum: "Inverse Fourier transform technique to determine second-order optical nonlinearity spatial profiles," Applied Physics Letters, Vol. 83, No. 8, 25 August 2003, p. 1679.	
	24	Ozcan, A., et al., "Post-processing of the second-order optical nonlinearity profile of thin films," Edward L. Ginzton Laboratory: Stanford University, Stanford, California 94305; ©2004 Optical Society of America, 2 pages.	
	25	Ozcan, A., et al., "Simplified inverse Fourier transform technique to determine second-order optical nonlinearity profiles using a reference sample," Electronics Letters, Vol. 40, No. 9, 29th April 2004, 2 pages.	
	26	Quatieri, Thomas F., Jr., et al., "Iterative techniques for minimum phase signal reconstruction from phase or magnitude," IEEE Trans. Acoust. Speech, Signal Processing, Vol. 29, 1981, pp. 1187-1193.	
SN	27	Rosenthal, Amir, et al., "Inverse Scattering Algorithm for Reconstructing Strongly Reflecting Fiber Bragg Gratings," IEEE Journal of Quantum Electronics, Vol. 39, No. 8, August 2003, pp. 1018-1026.	

1765092
061505

Examiner Signature	Sang Nguyen	Date Considered	7/7/05

*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

T[1] - Place a check mark in this area when an English language Translation is attached.

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. STANF.131CP2	APPLICATION NO. 10/645,331
SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT BY APPLICANT (USE SEVERAL SHEETS IF NECESSARY)	APPLICANTS Aydogan Ozcan et al.	
	FILING DATE August 21, 2003	GROUP 2124

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
GN	1	4,792,230	12/20/88	Naganuma et al.			
GN	2	5,530,544	06/25/96	Trebino et al.			
GN	3	6,456,380 B1	09/24/02	Naganuma			

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES	TRANSLATION NO
GN	4	JP 2000 329618 A	11/30/00	Japan				
GN	5	JP 2001 083015 A	03/30/01	Japan				
GN	6	PCT/US03/26311	08/21/03	PCT International Search Report dated 6/3/04				

EXAMINER INITIAL		OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

H:\DOCS\BSI\BSI-6171.DOC
062804

EXAMINER Gary Gurley	DATE CONSIDERED 07/07/05

*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. STANF.131CP2	APPLICATION NO. 10/645,331
SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT BY APPLICANT (USE SEVERAL SHEETS IF NECESSARY)	APPLICANTS Aydogan Ozcan et al.	
	FILING DATE August 21, 2003	GROUP ~~2124~~ 2877

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

EXAMINER INITIAL		OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)
GW	1	Kashyap, Raman, et al., *Phase-matched second harmonic generation by periodic poling of fused silica,* APPLIED PHYSICS LETTERS, Vol. 64, No. 11, 14 March 1994, pp. 1332-1334.
GW	2	Ozcan, A., et al., *Inverse Fourier transform technique to determine second-order optical nonlinearity spatial profiles,* APPLIED PHYSICS LETTERS, Vol. 82, No. 9, 3 March 2003, pp. 1362-1364.
	3	"Invitation to Pay Additional Fees" from the International Searching Authority regarding corresponding PCT Application No. PCT/US 03/26311, filed August 21, 2003, including Annex to Form PCT/ISA/206, "Communication Relating to the Results of the Partial International Search."
GW	4	Qui, Mingxin, et al., *Erratum: "Double fitting of Marker fringes to characterize near-surface and bulk second-order nonlinearities in poled silica,"* APPLIED PHYSICS LETTERS, Vol. 77, No. 23, 4 December 2000, p. 3863.

H:\DOCS\BSI\BSI-5361.DOC
030204

EXAMINER	DATE CONSIDERED 7/25/05

*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED. INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. STANF.131CP2	APPLICATION NO. 10/645,331
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (USE SEVERAL SHEETS IF NECESSARY)	APPLICANTS Aydogan Ozcan et al.	
	FILING DATE August 21, 2003	GROUP Unknown

EXAMINER INITIAL		OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)
GN	1	Alley, Thomas G., et al., *Space charge dynamics in thermally poled fused silica,* Journal of Non-Crystalline Solids 242 (1998), pp. 165-176.
	2	Bonfrate, G., et al., *Parametric fluorescence in periodically poled silica fibers,* Applied Physics Letters, Vol. 75, No. 16, October 18, 1999, pp. 2356-2358.
	3	Faccio, D., et al., *Dynamics of the second-order nonlinearity in thermally poled silica glass,* Applied Physics Letters, Vol. 79, No. 17, October 22, 2001, pp. 2687-2689.
	4	Fisher, Robert A., et al., *Transient analysis of Kerr-like phase conjugators using frequency-domain techniques,* PHYSICAL REVIEW A, Vol. 23, No. 6, June 1981, pp. 3071-3083.
	5	Kazansky, P.G., et al., *Thermally poled silica glass: Laser induced pressure pulse probe of charge distribution,* Applied Physics Letters, Vol. 68, No. 2, January 8, 1996, pp. 269-271.
	6	Liu, Alice C., et al., *Advances in the measurement of the poled silica nonlinear profile,* SPIE Vol. 3542, November 1998, pp. 115-119.
	7	Maker, P.D., et al., *Effects of Dispersion and Focusing on the Production of Optical Harmonics,* Physical Review Letters, Vol. 8, No. 1, January 1, 1962, pp. 21-22.
	8	Millane, R.P., *Analytic Properties of the Hartley Transform and their Implications,* PROCEEDINGS OF THE IEEE, Vol. 82, No. 3, March 1994, pp. 413-428.
	9	Miller, D.A.B., *Time reversal of optical pulses by four-wave mixing,* OPTICS LETTERS, Vol. 5, No. 7, July 1980, pp. 300-302.
	10	Myers, R.A., et al., *Large second-order nonlinearity in poled fused silica,* OPTICS LETTERS, Vol. 16, No. 22, November 15, 1991, pp. 1732-1734.
	11	Nakajima, N., *Reconstruction of a real function from its Hartley-transform intensity,* J. Opt. Soc. Am. A., Vol. 5, No. 6, June 1988, pp. 858-863.
	12	Pureur, D., et al., *Absolute measurement of the second-order nonlinearity profile in poled silica,* OPTICS LETTERS, Vol. 23, No. 8, April 15, 1998, pp. 588-590.
	13	Qiu, Mingxin, et al., *Double fitting of Maker fringes to characterize near-surface and bulk second-order nonlinearities in poled silica,* Applied Physics Letters, Vol. 76, No. 23, June 5, 2000, pp. 3346-3348.
	14	Quiquempois, Y., et al., *Localisation of the induced second-order non-linearity within Infrasil and Suprasil thermally poled glasses,* Optics Communications 176, April 1, 2000, pp. 479-487.
	15	Sun, P.C., et al., *Femtosecond pulse imaging: ultrafast optical oscilloscope,* J. Opt. Soc. Am. A, Vol. 14, No. 5, May 1997, pp. 1159-1170.
	16	Watanabe, Shigeki, et al., *Compensation of Chromatic Dispersion in a Single-Mode Fiber by Optical Phase Conjugation,* IEEE PHOTONICS TECHNOLOGY LETTERS, Vol. 5, No. 1, January 1993, pp. 92-95.
	17	Weiner, Andrew M., et al., *Femtosecond Pulse Shaping for Synthesis, Processing, and Time-to-Space Conversion of Ultrafast Optical Waveforms,* IEEE JOURNAL OF SELECTED TOPICS IN QUANTUM ELECTRONICS, Vol. 4, No. 2, March/April 1998, pp. 317-331.
	18	Weiner, Andrew M., et al., *Femtosecond Spectral Holography,* IEEE JOURNAL OF QUANTUM ELECTRONICS, Vol. 28, No. 10, October 1992, pp. 2251-2256.
	19	Yariv, Amnon, et al., *Compensation for channel dispersion by nonlinear optical phase conjugation,* OPTICS LETTERS, Vol. 4, No. 2, February 1979, pp. 52-54.
SW	20	Ferreira, Paulo Jorge S.G., *Interpolation and the Discrete Papoulis-Gerchberg Algorithm,* IEEE TRANSACTIONS ON SIGNAL PROCESSING, Vol. 42, No. 10, October 1994, pp. 2596-2606.

H:\DOCS\BSI\BSI-4851.DOC:sam\120103

EXAMINER Gaughan	DATE CONSIDERED 07/07/05

*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.